OPTOELECTRONIC SOURCE MEASUREMENT SYSTEM MODEL 58602

BURN-IN, RELIABILITY & LIFE TEST

Chroma 58602 is a high density, precision multi Source Measurement Unit (SMU) Module with temperature control and exchangeable interface developed for Burn-In, Reliability and Life Test of Optoelectronic Components including Laser Diodes, LEDs, OLEDs, Photo-Diodes and other similar components. Each Module has up to 768 discrete SMUs (6 modules contain up to 4608 SMUs per System), which may be used as Device Drives, Device Biasing and/or Measurement Operations. The system's high density allows for optimized clean room space.

SOURCE AND MEASUREMENT

Discrete voltage measurements are available for high current devices placed in series. Multiple Current sources may also be paralleled (exchanging the Conversion Interface Board) to support higher power devices.

ULTIMATE FLEXIBILITY

Chroma brings the Change Kit flexibility used in the semiconductor industry to optoelectronics. Through the Change Kit the 58602 can be configured to other devices in minutes for:

- High Channel Density
- Higher Currents
- Optical Power Monitoring
- Monitor Photodiode Measurements
- Dark Current Measurements
- Component Biasing
- Multiple Device Types

EFFICIENT PROCESSING

- Higher temperatures reduce aging times and provide quicker results while lowering cost by requiring lower channels.
- The High Density Design reduces floor space over other similar solutions.
- Batch processing is performed through device carriers. Carriers may be used between Aging and Characterization Testing. Software tracks acquired data between all Chroma testing.
- Same base system may be used for many device types. A Conversion Kit provides quick, cost effective adaptation to prototypes and new products or variation in production.
- Hot Swappable power supplies eliminate this type of failure mode while reducing MTBF / MTTR.



KEY FEATURES

- Burn-In, Reliability and Life Testing
- Up to 4608 Channels
- Up to 20A per device
- Up to 150°C
- Batch processing via device carriers
- Change Kit adapts to multiple devices

SPECIFICATIONS

evice Specifications:					
	Feature	Definition			
Devisor	Component Types	Laser Diodes, LEDs, OLEDs, SLEDs, Photodiode, MPDs CoS / CoC, TO-Can, C-Mount, Custom			
Devices	Package Types				
Module Specifications:					
	Range	Resolution	Uncertainty Accuracy ±(%Value + offset)	Random Uncertainty (Stability)	Max Devices Per Modul System
Wavelength	380 nm – 1700 nm				
Temperature Control (Life Test)	40°C - 150°C	0.1°C	± (2.0% + 1°C)	1°C	
Temperature Control (I-V)	30°C - 50°C	0.1°C	±(2.0% + 1°C)	1°C	
58602-022					768 / 4608
Source/Measure Voltage	0-3.00 V	175 <i>µ</i> V	1% + 5 mV	5 mV	
Source/Measure Current	0-250 mA*	48 µA	1% + 480 µA	480 µA	
Power Measurement	0 – 250 mW	250 µW	$(20\% + 500 \mu\text{W})$	2500 μW	
58602-013					384 / 2304
Source/Measure Voltage	1.50 - 4.00 V	76.3 μV	2% + 30 mV	30 mV	
Source/Measure Current	0-1250 mA	38.3 µA	2% + 12.5 mA	12.5 mA	
Current Pulsing	200 µs - CW	100 μ s Rise / 10 μ s Fall (typical)	1% Overshoot	10 µ Settling Time	
Power Measurement (CW Only)	0 – 1500 mW	5 mW	(20% + 500 µW)	2500 µW	
58602-023					192 / 1152
Source/Measure Voltage	1.50 - 4.00 V	76.3 μV	2% + 30 mV	30 mV	
Source/Measure Current	0-2500 mA	76.6 µA	2% + 25 mA	25 mA	
Current Pulsing	200 µs - CW	100 μ s Rise / 10 μ s Fall (typical)	1% Overshoot	10 μs Settling Time	
Power Measurement (CW Only)	0 – 2500 mW	5 mW	(20% + 500 μW)	2500 μW	
58602-053				,	96 / 576
Source/Measure Voltage	0-5.00 V	175 μV	1% + 5 mV	5 mV	
Source/Measure Current	0-5000 mA**	, 180 μA	0.1% + 2.5 mA	1.0 mA	
Power Measurement	0 – 5000 mW	5 mW	(20% + 500 μW)	2500 μW	
58602-053S				,	960 / 5760
Source/Measure Voltage	20-50.0 V	175 mV	1% + 10 mV	30 mV	Up To 20 Devices
Source/Measure Current	500 - 5000 mA**	180 µA	2% + 2.5 mA	25 mA	In Series
Power Measurement	0– 5000 mW	5 mW	(20% + 500 μW)	2500 μW	
odule & System Specifications:	0 0000 1111	0	(20/0 1 000 µ 11)	2000 μ.11	
	Feature	Definition	Minimum	Maximum	
Module	Carriers Per Module***	Bennition	1	6	
Wodule	Data Sample Time	10 sec - 48 hrs	1	0	
	Communication	Ethernet - TCP/IP			
	Change Kit Device Adaptability				
	User Site Calibration/Validation				
	Internal Water Leak Detectors	Yes			
		res	40°C	150°C	
	Device Temperature ****				
System	Modules Per System		1	6	
	System Per Server		1	2	
	System Thermal Deviation	5°C			
	System Internal Power	High Reliable, Redundant, Hot Swappable Power Supply			
	Water Leak Shut Down	System Level (Optional)			
System Requirements	Power Requirement *****		or 187 to 250 VAC		
	Water Temperature	20°C ± 2	18°C	20°C	
	Water Flow (per Module)	3 to 6 Liters/Min			
	Ambient Temperature	23°C ± 5°C			
	Ambient Relative Humidity	< 60 %RH (Non Condensing)			
	Rack Size (HxWxD)	80.5" x 23" x 44"			

* 58602-022: 8 channels may be paralleled to source up to 2-Amps per device.

** 58602-053 & -053S: 4 channels may be paralleled to source up to 20-Amps per device.

*** For discrete drive systems, Series sources vary per device power

**** Typical thermal control range is 40°C

***** Series drive source varies dependent on device power.

Developed and Manufactured by : CHROMA ATE INC.

HEADQUARTERS

U.S.A. 7 Chrysler, Irvine, CA 92618 Tel: +1-949-421-0355 Fax: +1-949-421-0353 Toll Free: +1-800-478-2026 www.chromaus.com info@chromaus.com

No. 66, Hwaya Rd. 1, Hwaya Technology Park, Kueishan 33383, Taoyuan, Taiwan Tel: +886-3-327-9999 Fax: +886-3-327-8989 www.chromaate.com chroma@chroma.com.tw

HSINCHU

6F, No. 5, Technology Rd., Hsinchu Science Park, Hsinchu 30078, Taiwan Tel: +886-3-563-5788 Fax: +886-3-563-5758

JAPAN

Chroma Japan Corp. Shin Yokohama Nara Building 11F 2-2-8 ,Shin Yokohama, Kouhoku-ku, Yokohama-shi, Kanagawa, 222-0033 Japan Tel:+81-45-470-2285 Fax:+81-45-470-2285 Fax:+81-45-470-2287 URL: www.chroma.co.jp Email: chroma@chroma.com.tw

EUROPE

Morsestraat 32, g 11F NL-6716 AH Ede, The Netherlands Tel: +31-318-648282

CHINA

3F Building 40, No. 333, Qin Jiang Rd., Shanghai, China PC: 200233 Tel: +86-21-6495-9900 Fax: +86-21-6495-3964